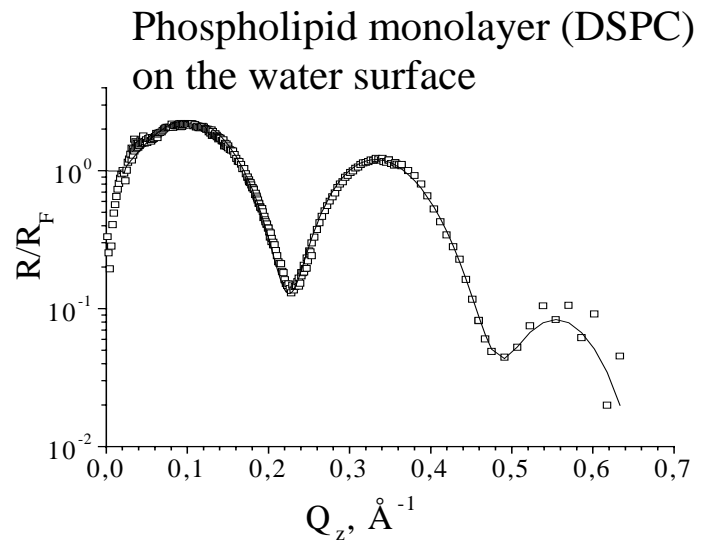
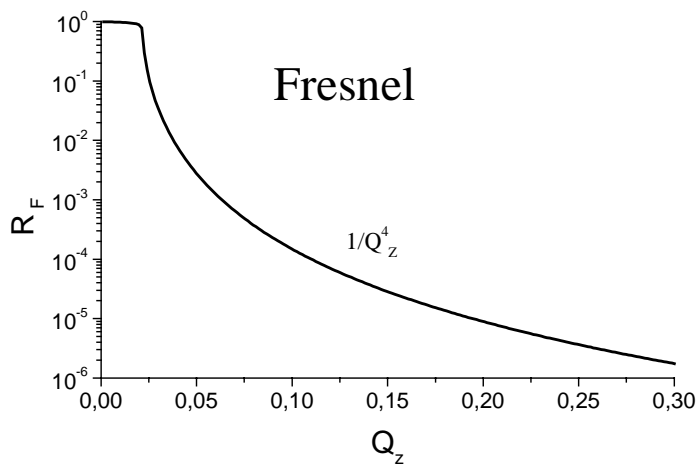
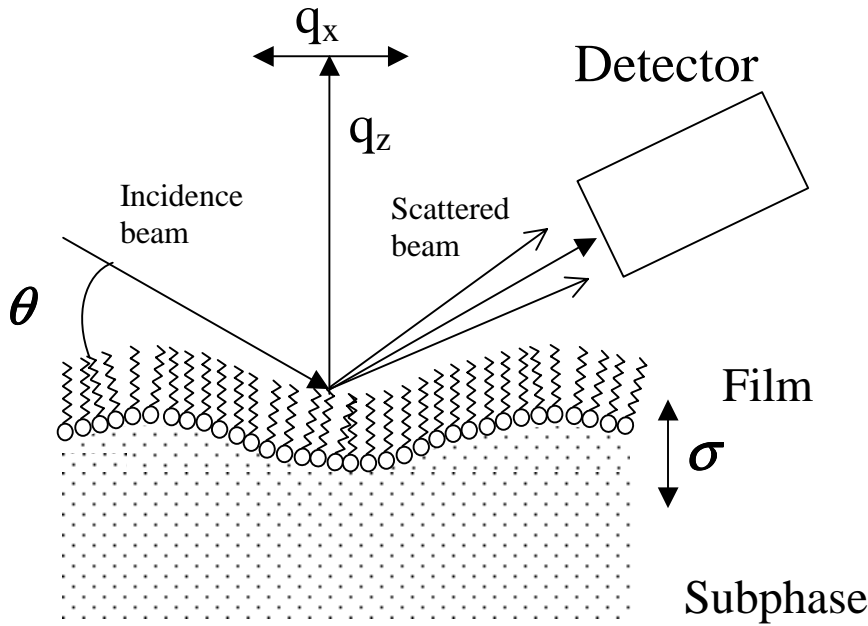


# What is it X-ray reflectivity ?



$$I/I_0 = R_F(q_z) |\Phi(q_z)|^2 ; \text{ where } |\Phi(q_z)| = \text{F.T.} [\partial \rho(z) / \partial z]$$

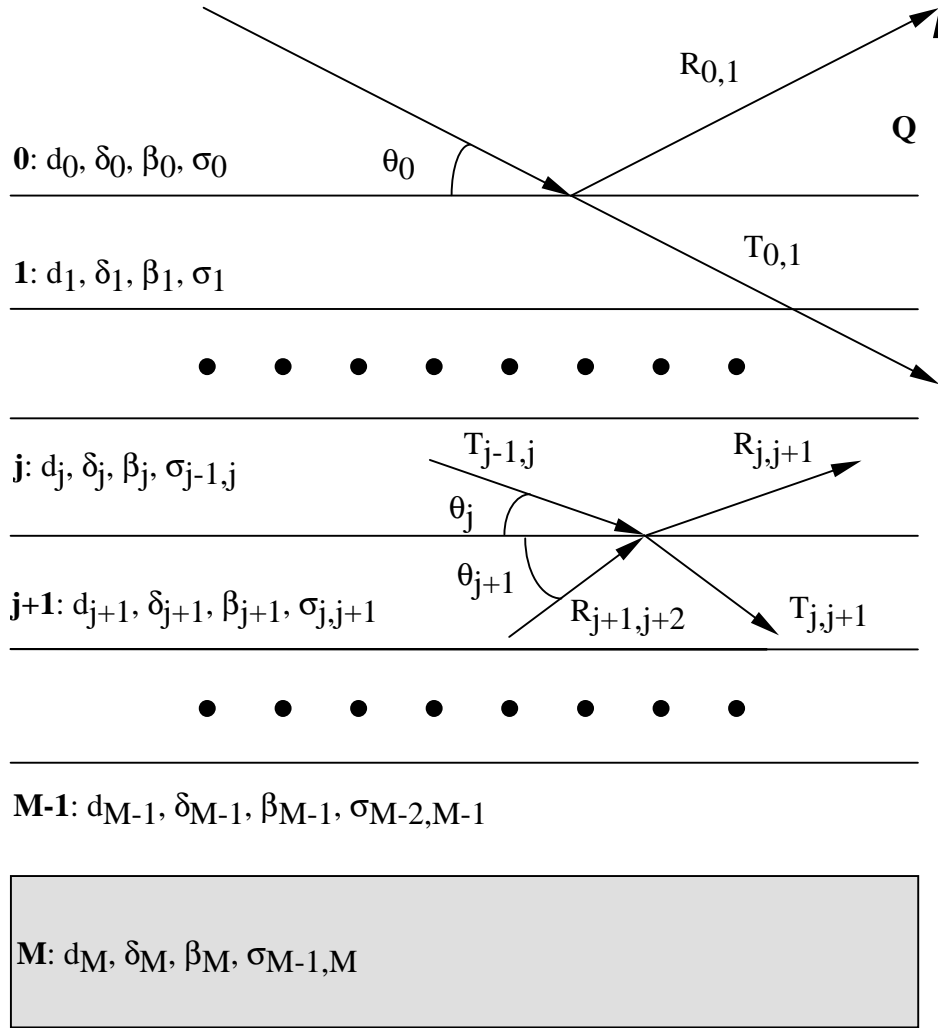
In case of roughness  $\sigma$  (identical for all interfaces) the formula should be corrected for Debye Waller factor accounting for the roughness

$$I/I_0 = R_F(q_z) |\Phi(q_z)|^2 \exp(-q_z^2 \sigma^2)$$

**From specular reflectivity one can derive**

- ⇒ **The electron density profile  $\rho(z)$  at interface of two media**
- ⇒ **The surface/interfaces roughness  $\sigma$**

# Reflectivity calculation (Parratt version)



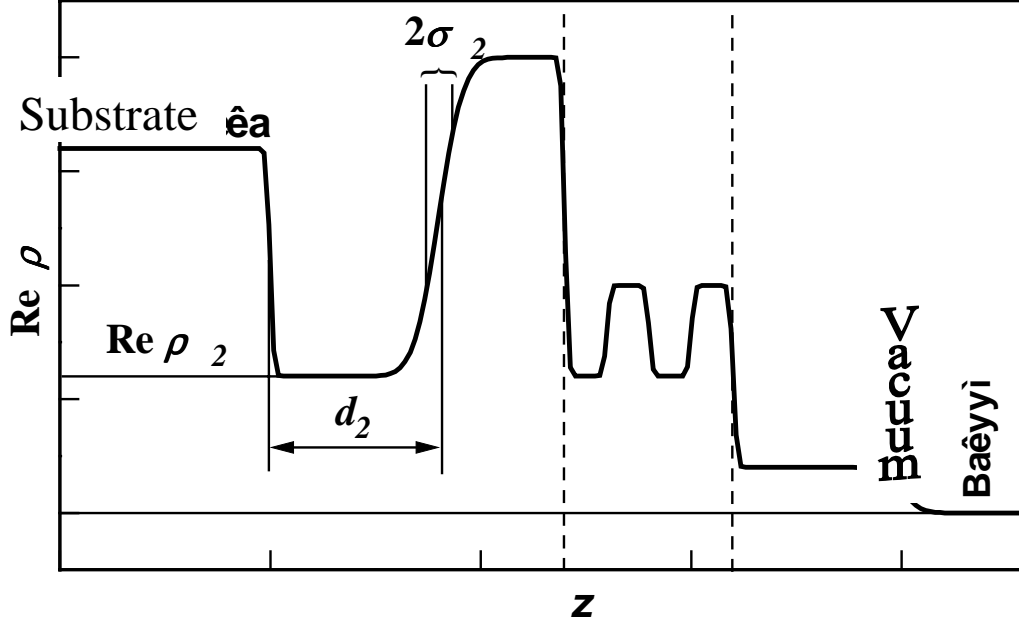
Reflectivity is  $I(\theta) = |R_{0,1}(\theta)|^2$ , where  $R_{0,1}(\theta)$  is calculated from recursive formula

$$R_{n-1,n} = a_{n-1}^4 \cdot \left| \frac{R_{n,n+1} + F_{n,n-1}}{1 + R_{n,n+1} F_{n-1,n}} \right|$$

$R_{n,n+1} = a_n^2 \times E_n^R / E_n$ ,  $F_{n-1,n} = (\eta_{n-1} - \eta_n) / (\eta_{n-1} + \eta_n)$ ,  $\eta_n = (N_n^2 + \cos^2(\theta))^{1/2}$ ,  $a_n = \exp(-ik\eta_n d_n / 2)$ ,  $n=0,1,2,\dots,M$ ;  
 $k=2\pi/\lambda$ ,  $\lambda$ - wave length,  $E_n$ ,  $E_n^R$  – amplitudes of transmitted and reflected fields in the layer  $n$ ,  $d_n$  – thickness of layer  $n$ , material index  $N_n = 1 - \delta_n - i\beta_n$ ;  $n=M$  for substrate,  $R_{M,M+1}=0$ .

## Scattering density profile parameterization.

$$\Gamma = \left\{ N_m, \left\{ d_{mj}, \rho_{mj}, \sigma_{mj} \right\}_{j=1}^{M_m} \right\}_{m=1}^G$$



## Calculation of reflectivity $R$

Matrix of the structure:

$$\mathbf{A} = \prod_{m=1}^G \mathbf{U}_m \mathbf{A}_m^{N_m} \mathbf{W}_m; \quad R = \left| \frac{a_{21}}{a_{11}} \right|^2$$

Power of the matrix  $\mathbf{Y}$  ( $\det \mathbf{Y} = 1$ ):

$$\mathbf{Y}^N = \begin{pmatrix} y_{11} T_{N-1}(x) - T_{N-2}(x) & y_{12} T_{N-1}(x) \\ y_{21} T_{N-1}(x) & y_{22} T_{N-1}(x) - T_{N-2}(x) \end{pmatrix},$$

$$x = (y_{11} + y_{22}) / 2,$$

$$T_N(x) = \frac{\sin[(N+1) \arccos x]}{\sqrt{1-x^2}}.$$

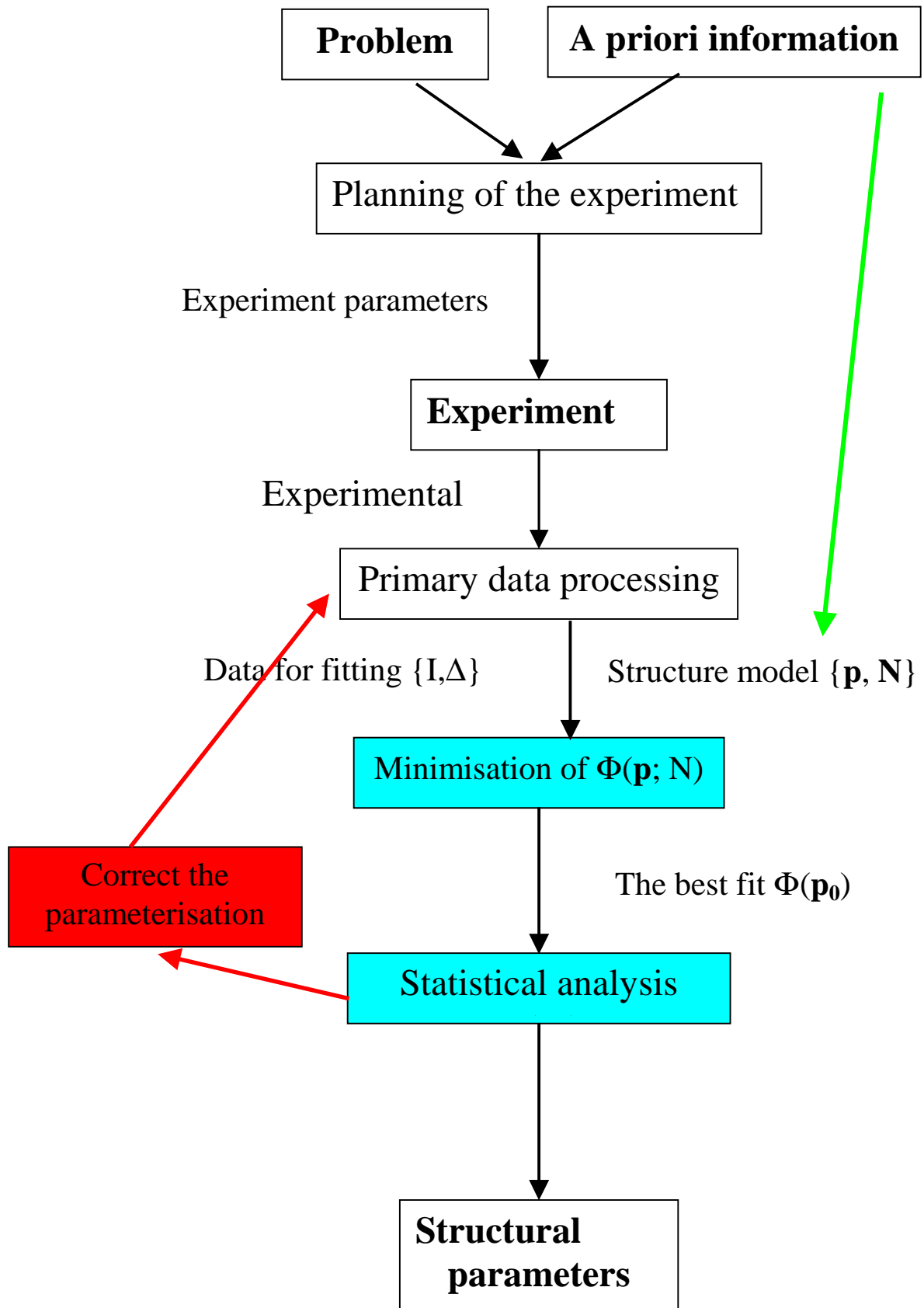
Matrix of a layer:

$$\mathbf{A}_k = \left\| \begin{array}{cc} [1 - (r_k^F)^2]^{-1/2} \exp(-ib_k d_k) & r_k^F [1 - (r_k^F)^2]^{-1/2} \exp(ib_k d_k) \\ r_k^F [1 - (r_k^F)^2]^{-1/2} \exp(-ib_k d_k) & [1 - (r_k^F)^2]^{-1/2} \exp(ib_k d_k) \end{array} \right\|,$$

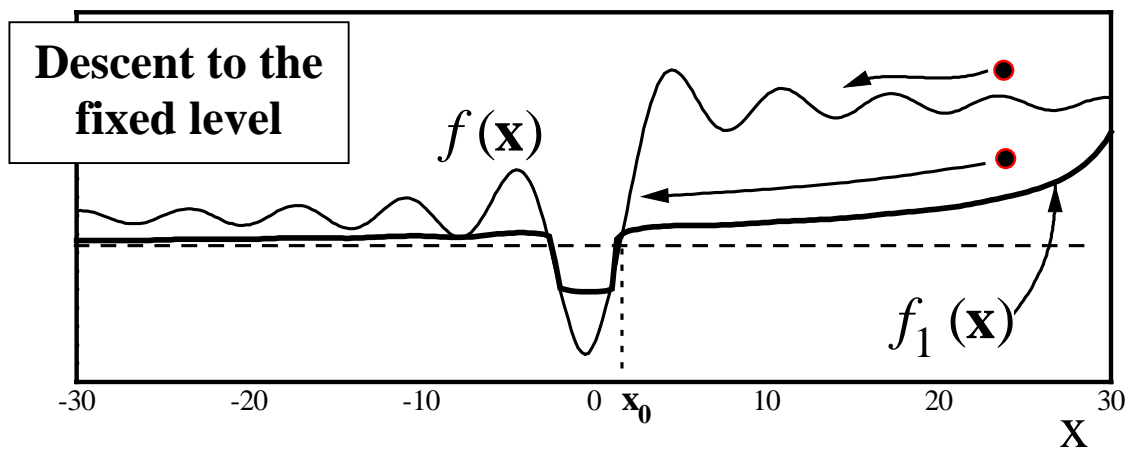
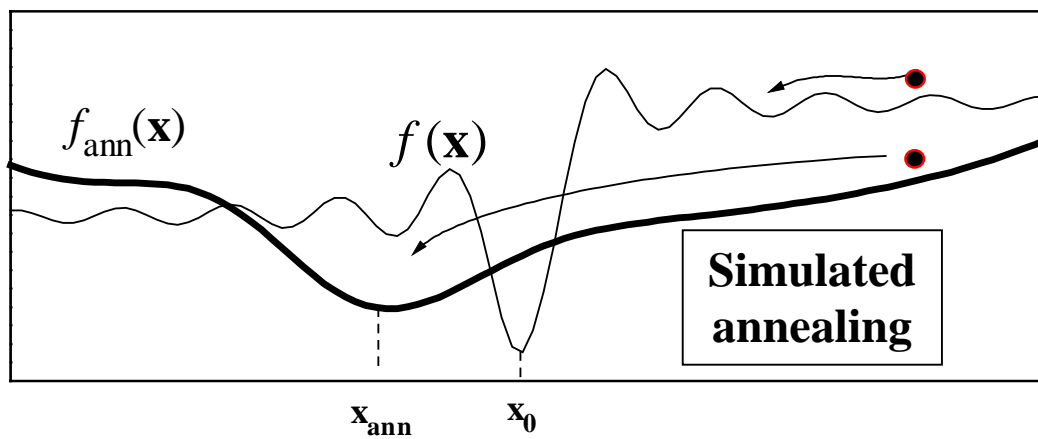
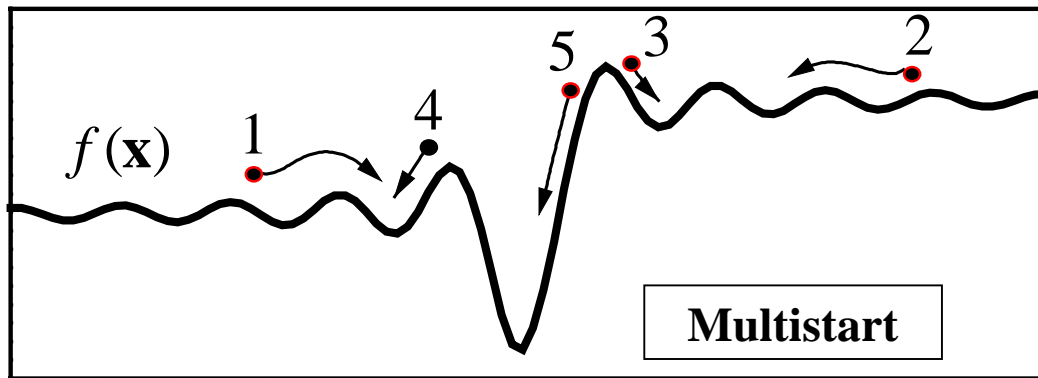
$$b_k = 1 / 2 \cdot \sqrt{Q^2 - 2\pi \rho_k}, \quad Q = \frac{4\pi}{\lambda} \sin \theta,$$

$$r_k^F = \frac{b_k - b_{k+1}}{b_k + b_{k+1}} \cdot \exp(-2 b_k b_{k+1} \sigma_k^2), \quad k = 1, \dots, N_t.$$

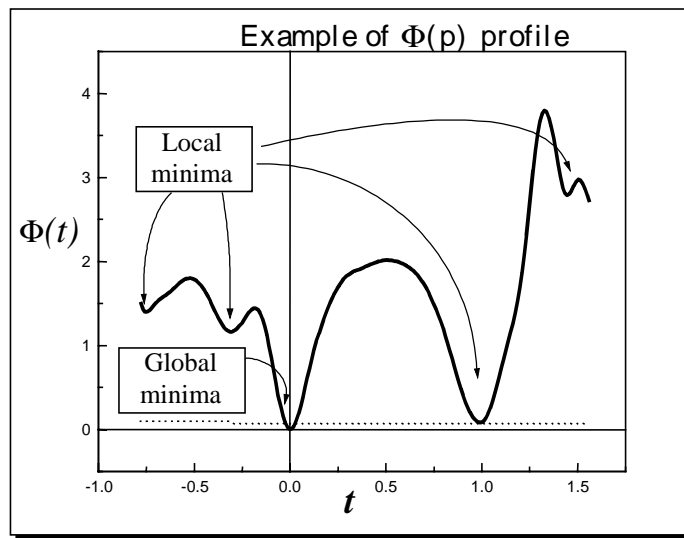
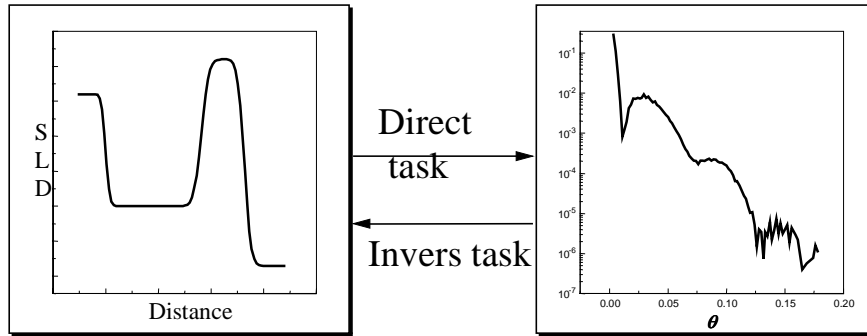
# Generalized scheme of reflectivity data treatment



## Some techniques of global minimization



## The objective function minimization



## The objective function of fitting $\Phi(\mathbf{p})$

$$\Phi(\mathbf{p}) = \frac{B}{L - P} \cdot \sum_{c=1}^C \sum_{l=1}^{L_c} \left( \frac{I_{\text{exp}}(Q_{cl}) - S_c I(Q_{cl}, \Gamma(\mathbf{p}))}{\Delta_{cl}} \right)^2,$$

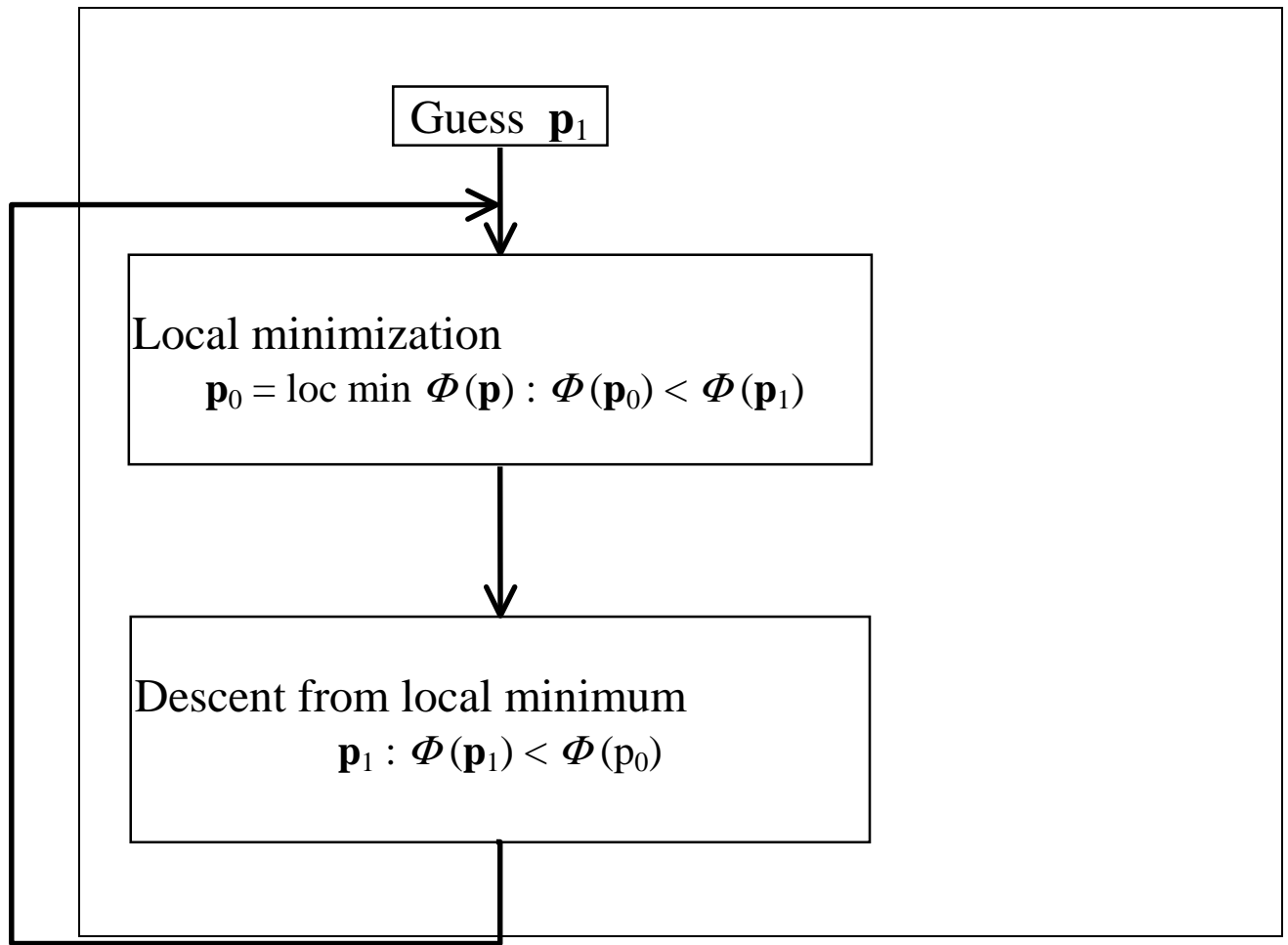
$$L = \sum_{c=1}^C L_c, \quad B = \left( \sum_{c=1}^C \sum_{l=1}^{L_c} \left( \frac{I_{\text{exp}}(Q_{cl})}{\Delta_{cl}} \right)^2 \right)^{-1},$$

$$S_c = \frac{\sum_{l=1}^{L_c} \frac{I_{\text{exp}}(Q_{cl}) \cdot I(Q_{cl}, \Gamma(\mathbf{p}))}{\Delta_{cl}^2}}{\sum_{l=1}^{L_c} \frac{(I(Q_{cl}, \Gamma(\mathbf{p})))^2}{\Delta_{cl}^2}}.$$

## The domain of minization

$$\Omega = \left\{ \mathbf{p} : \left\{ p_k^{\text{min}} < p_k < p_k^{\text{max}} \right\}_{k=1}^P \right\}$$

## Method of successive descent from local minima ( $\Phi^* = \Phi(\mathbf{p}_0)$ )



Modification of the objective

$$\Phi_1 = \frac{\Phi(\mathbf{p}) - \Phi(\mathbf{p}_0)}{\|\mathbf{p} - \mathbf{p}_0\|^\alpha}$$

Descent condition (go away from  $\mathbf{p}_0$ )

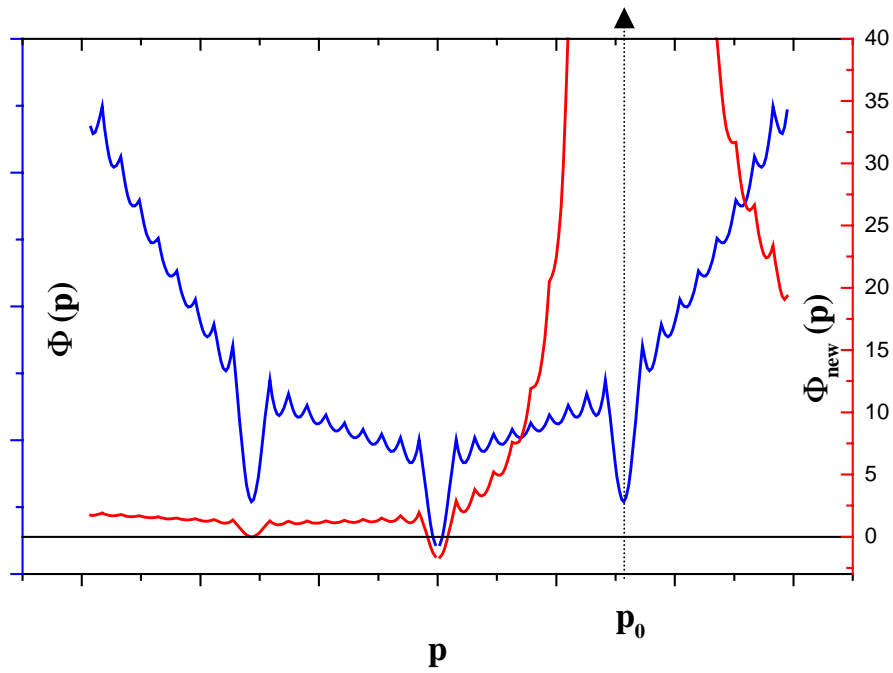
$$((\nabla \Phi_1(\mathbf{p})) \cdot (\mathbf{p} - \mathbf{p}_0)) < 0 ;$$

$$\alpha > \frac{1}{2} \left( \frac{\nabla \Phi(\mathbf{p})}{\Phi(\mathbf{p}) - \Phi(\mathbf{p}_0)} \right) \cdot (\mathbf{p} - \mathbf{p}_0)$$

# Geometric interpretation of the objective function modification.

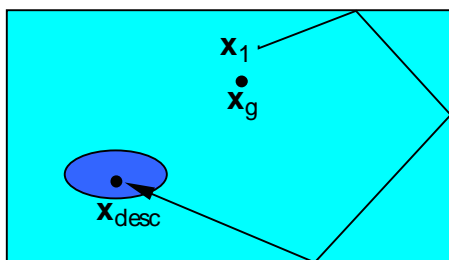
modified objective function

$$\Phi_{new} = \frac{\Phi(\mathbf{p}) - \Phi(\mathbf{p}_0)}{(\mathbf{p} - \mathbf{p}_0, \mathbf{p} - \mathbf{p}_0)^\alpha}$$



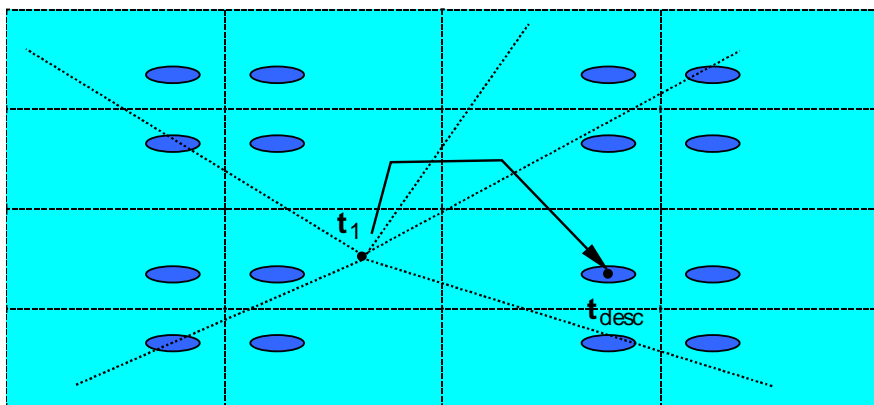


## Trajectory of the probing point

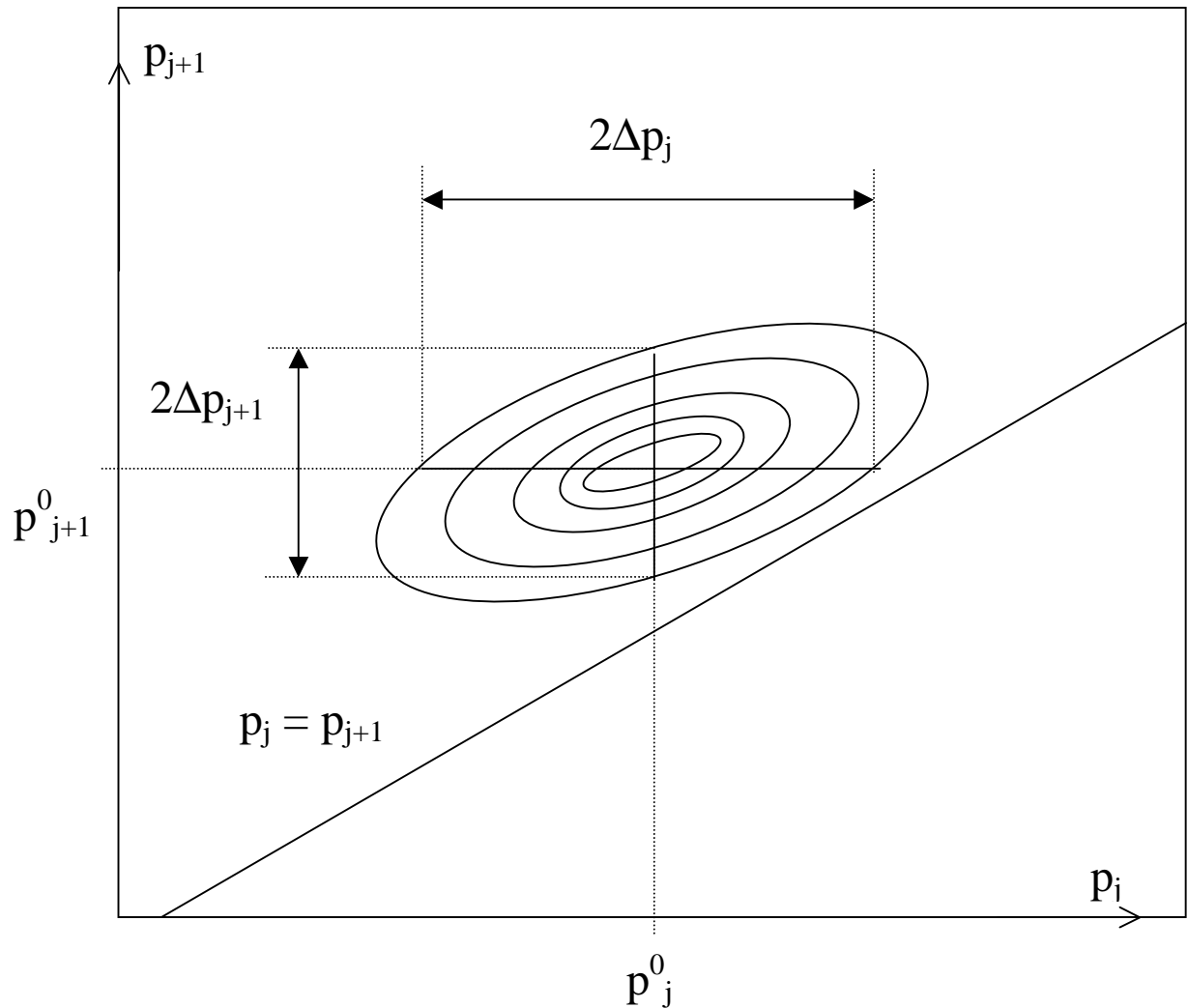


Periodic extension of the domain of interest

$$p_k = \frac{p_k^{\max} + p_k^{\min}}{2} + \frac{p_k^{\max} - p_k^{\min}}{2} \sin t_k, \quad k = 1, \dots, P.$$



# Geometric interpretation of the hypothesis about equivalence of two parameters



ellipses are confidence domain.

$\Delta p_j^0$  and  $\Delta p_{j+1}^0$  are confidence intervals

line  $p_j = p_{j+1}$  is hypothesis

Hypothesis is accepted when its intersection with the confidence domain is not empty with certain confidence level.

# Statistical analysis

Matrix of equations  $\mathbf{X}$  and inverse covariance matrix  $\mathbf{C}^{-1}$

$$X_{ij} = \sqrt{B} \frac{S_i(\mathbf{p}_0)}{\Delta_i} \frac{\partial I(Q_i, \Gamma(\mathbf{p}))}{\partial p_j} \bigg|_{\mathbf{p}=\mathbf{p}_0},$$

$$\mathbf{C}^{-1} = (\mathbf{X}^T \mathbf{X})^{-1}.$$

**Significance of parameters.** Testing hypothesis

$$d_j = 0;$$

$$\sigma_j = 0;$$

$$\text{Im } \rho_j = 0;$$

$$\text{Re } \rho_j = \text{Re } \rho_{j-1}; \text{Re } \rho_j = \text{Re } \rho_{j-1}$$

Statistics:

$$F_1 = \frac{(u_j - \mu)^2}{\Phi_g \cdot (\mathbf{C}^{-1})_{jj}},$$

$$F_2 = \frac{(u_j - u_{j-1})^2}{\Phi_g \cdot \left( (\mathbf{C}^{-1})_{jj} + (\mathbf{C}^{-1})_{j-1, j-1} - 2(\mathbf{C}^{-1})_{j, j-1} \right)}.$$

Criteria of the hypothesis acceptance:  $F_j < F_j(w_0)$ .

$F_j(w_0)$  - is quantile of confidence level  $w_0$  for  $F_{1,L-P}$  distribution

**Accuracy evaluation.** Confidence interval:

$$\Lambda_j(w_0) = [p_{0j} - \gamma \cdot \sqrt{\Phi_g \cdot (\mathbf{C}^{-1})_{jj}}, p_{0j} + \gamma \cdot \sqrt{\Phi_g \cdot (\mathbf{C}^{-1})_{jj}}]$$

$\gamma$ - is quantile of confidence level  $w_0$  for Student's distribution with  $(L-P)$  degrees of freedom

## Fisher's criterion (F-distribution)

How compare two model and made a choice between them ?

If two models  $\mathbf{p}_1$  (with rank  $M_1$ ) and  $\mathbf{p}_2$  (with rank  $M_2$ ) obtained independently on the base of  $N_1$  and  $N_2$  trials, accordingly, then to check up hypothesis about its equality useful to use ratio of residues

$$H_F = \frac{\Phi_{M_1}(\mathbf{p}_1)}{\Phi_{M_2}(\mathbf{p}_2)}$$

Statistic theory says that  $H_F$  obeys to, so called,  $F$ -distribution with  $(N_1-M_1)$  and  $(N_2-M_2)$  degrees of freedom. This distribution is known also as Fisher's criterion.  $F$ -distribution value for  $H_F$  gives probability that residues  $F_{M_1}(\mathbf{p}_1)$  and  $F_{M_2}(\mathbf{p}_2)$  of two model are not equal, and therefore lets make assumption about models

**F-distribution is**

$$F_{m,n}(x) = \frac{\Gamma\left(\frac{m+n}{2}\right)}{\Gamma\left(\frac{m}{2}\right)\Gamma\left(\frac{n}{2}\right)} \int_0^x \frac{\alpha^{\frac{m}{2}-1}}{(\alpha+1)^{\frac{m+n}{2}}} d\alpha$$

**In accordance with Fisher's criterion two model are statistically identical if the value of its statistics (the residues ratio) is lower than the quantile of the  $F_{N_1, N_2}$  distribution. This quantile is defined by the confidence level  $w_0$  and numbers of model parameters  $N_1$  and  $N_2$  ( $N_1 < N_2$ ).**

How verify hypothesis about parameters correlation ?

The simplest correlation between parameters is linear correlation.

$$\mathbf{A}\mathbf{p}_{opt} = \mathbf{v}$$

Where  $\mathbf{A}$  is known matrix  $n \times m$  ( $n$  number of independent parameters) and  $\mathbf{v}$  is known vector (with rank  $n$ ). In case of linear correlation is possible build statistic as

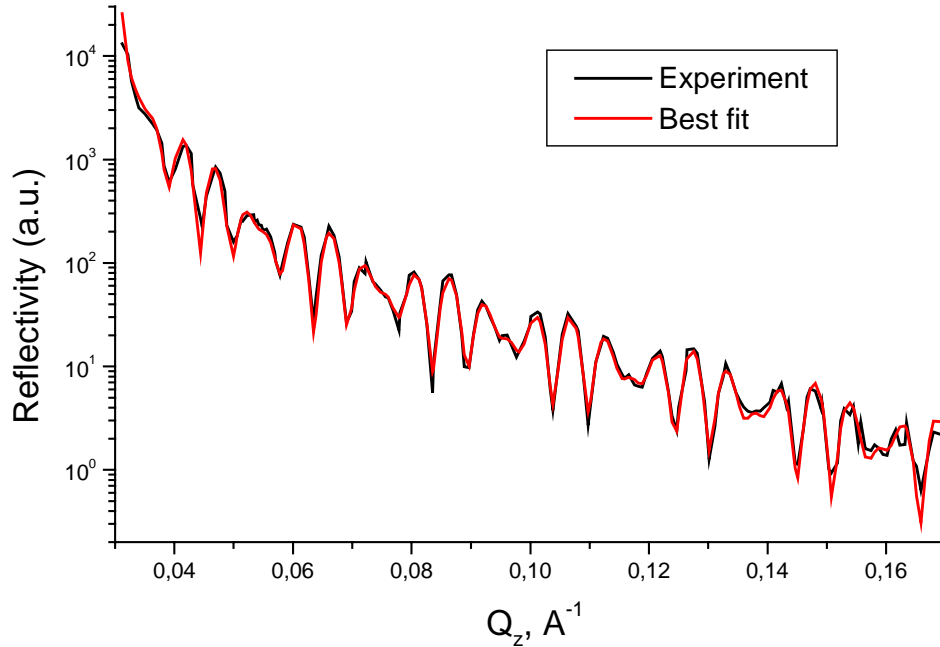
$$F_A = \frac{RSS_A - RSS}{n \Phi_M(\mathbf{p}_{opt})} = \frac{(\mathbf{A} \mathbf{p}_{opt} - \mathbf{v})^T (\mathbf{A} \mathbf{C}^{-1} \mathbf{A}^T)^{-1} (\mathbf{A} \mathbf{p}_{opt} - \mathbf{v})}{n \Phi_M(\mathbf{p}_{opt})}$$

which also obeys to  $F$ -distribution with  $m$  and  $N-M$  degrees of freedom

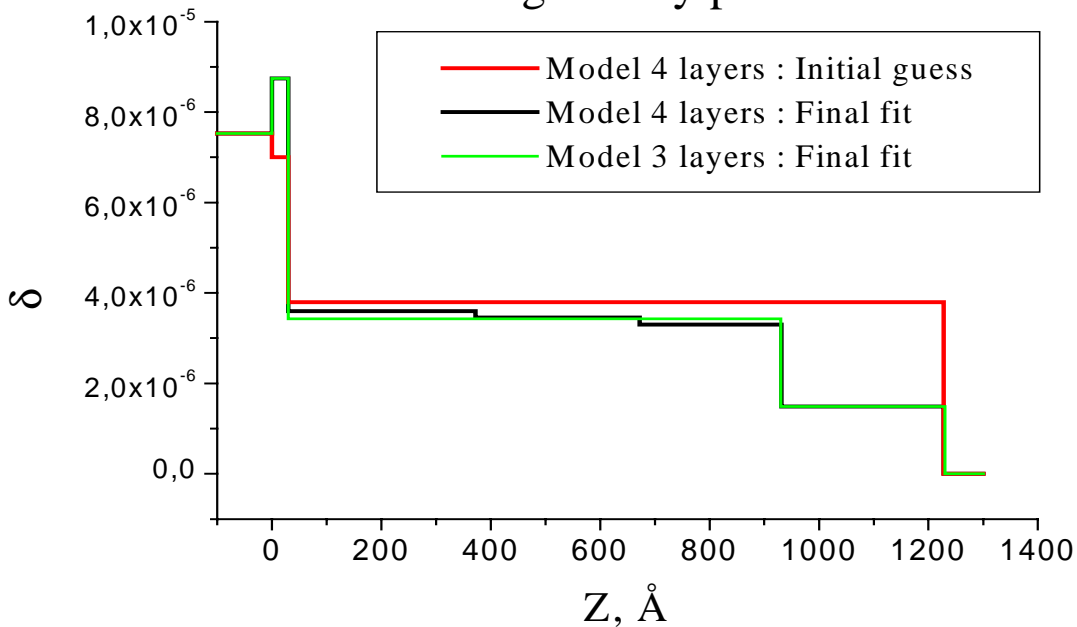
$RSS_A$  and  $RSS$  are  $\chi^2$  value for model with correlation and with out correlation.

# Example of use the program *REFLAN*

Modeling of scattering by system Si/SiO<sub>2</sub>/4 x (PS/PBMA)  
polystyrene / polybutylmethacrylate copolymer films spin-coated on Si substrates



## Scattering density profiles



Confidence intervals (confidence level  $w_0 = 0.68$ ):

$$\begin{aligned} \rho_4 &= 1.49 \cdot 10^{-6} \pm 0.4 \cdot 10^{-6}, & d_4 &= 300 \pm 15 \text{ Å.} \\ \rho_3 &= 3.43 \cdot 10^{-6} \pm 0.3 \cdot 10^{-6}, & d_3 &= 900 \pm 5 \text{ Å;} \\ \rho_2 &= 8.74 \cdot 10^{-6} \pm 2.1 \cdot 10^{-6}, & d_2 &= 30 \pm 5 \text{ Å;} \end{aligned}$$

